

**ADuM3190 Die Revision**

**Qualification Results Summary of ADuM3190 Die Revision**

<b>QUALIFICATION RESULTS</b>			
<b>TEST</b>	<b>SPECIFICATION</b>	<b>SAMPLE SIZE</b>	<b>RESULTS</b>
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	<b>9 x 77</b>	<b>Pass</b>
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	<b>9 x 77</b>	<b>Pass</b>
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	<b>9 x 77</b>	<b>Pass</b>
Unbiased Highly Accelerated Stress Test (uHAST)*	JEDEC <i>JESD22-A118</i>	<b>9 x 77</b>	<b>Pass</b>
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	<b>3 x 77</b>	<b>Pass</b>
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	<b>3 x 10</b>	<b>Pass</b>
Latch-Up	JEDEC <i>JESD78</i>	<b>1 x 9</b>	<b>Pass</b>
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	<b>3/voltage</b>	<b>Pass 4.0kV</b>
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	<b>3/voltage</b>	<b>Pass 1.25kV</b>

\*Preconditioned per JEDEC/IPC J-STD-020